Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Threshold Voltage N-Channel	V_{THN}	-	CLR Input at Ground All Other Inputs: V_{IN}=5V V_{DD}=5V, I_{SS}=-10µA T_{amb}=+125°C T_{amb}=- 55°C	-0.3 -0.7	-3.5 -3.5	V
Threshold Voltage P-Channel	V_{THP}	-	CLR Input at Ground All Other Inputs: V_{IN}=-5V V_{SS}=-5V, I_{DD}=10µA T_{amb}=+125°C T_{amb}=- 55°C	0.3 0.7	3.5 3.5	V

2.3.3   Notes to Electrical Measurement Tables

1. Unless otherwise specified all inputs and outputs shall be tested for each characteristic, inputs not under test shall be $V_{IN} = V_{SS}$ or V_{DD} and outputs not under test shall be open.
2. Functional tests shall be performed to verify Truth Table with $V_{OH} \geq V_{DD}$ -0.5V, $V_{OL} \leq$ 0.5V. The Maximum time to output comparator strobe = 300µs.
3. Quiescent Current shall be tested using the following input conditions:
    (a) Input CLR = V_{IH} ; Input CLK = V_{IL}.
    (b) Input CLR = CLK = V_{IL}.
    (c) Input CLR = V_{IL} ; 5461 pulses applied to CLK to configure outputs QE, QG, QI, QM to high level.
    (d) Input CLR = V_{IL} ; 5461 additional pulses applied to CLK to configure outputs QD, QF, QH, QJ, QL, QN to a high level.
    (e) Input CLR = V_{IL} ; 5461 additional pulses applied to CLK to configure all outputs QD to QN to a high level.
    (f) Input CLR = V_{IL} ; 1 additional pulse applied to CLK to configure all outputs QD to QN to a low level.

4. Interchange of forcing and measuring parameters is permitted.
5. Input Clamp Voltage 2 to V_{DD}, V_{IC2}, shall be tested on each input as follows:-